

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/646,152	PARK ET AL.
	Examiner	Art Unit
	Shih-Chao Chen	2821

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
343	700MS	5/23/2005	CHEN
343	702	5/23/2005	CHEN